

METHOD AND SYSTEM FOR DISTRIBUTED TESTING  
OF ELECTRONIC DEVICES

ABSTRACT OF THE DISCLOSURE

A distributed tester method and system communicates test recipes for testing electronic devices from a host computer over a network to a test site. The test site translates test recipes into test instructions for execution by a test engine that determines the status of the electronic device. For instance, in a tester for testing memory, a test recipe is defined and stored with a host computer to determine test data for storage on the memory device under test at the test site. The host computer controls execution of the test recipe over the network. The test recipe is defined and stored in an XML formatted data file transmitted over the network to a processor at the test site. The test site processor translates the XML formatted data into test instructions for execution by a test engine. The test engine determines whether the memory device under test accurately stores data and provides the results, such as erroneously stored data, to the host computer through the network. A test design host and a global data master also interface with the network to aid the design and storage of test recipes. The distributed test method and system advantageously improves flexibility of testing over a geographically disbursed area and with divergent test recipes and devices under test.